


<b>Search Notes</b>  	<b>Application/Control No.</b>  10524632	<b>Applicant(s)/Patent Under Reexamination</b>  NAWATA, HIDEO
	<b>Examiner</b>  KRISTEN C MATTER	<b>Art Unit</b>  3771

SEARCHED			
Class	Subclass	Date	Examiner
128	205.11, 205.12, 204.18, 204.21, 204.23, 204.25, 204.26	7/25/08	KCM
95	96	7/25/08	KCM

SEARCH NOTES		
Search Notes	Date	Examiner
Inventor name search	7/25/08	KCM

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner